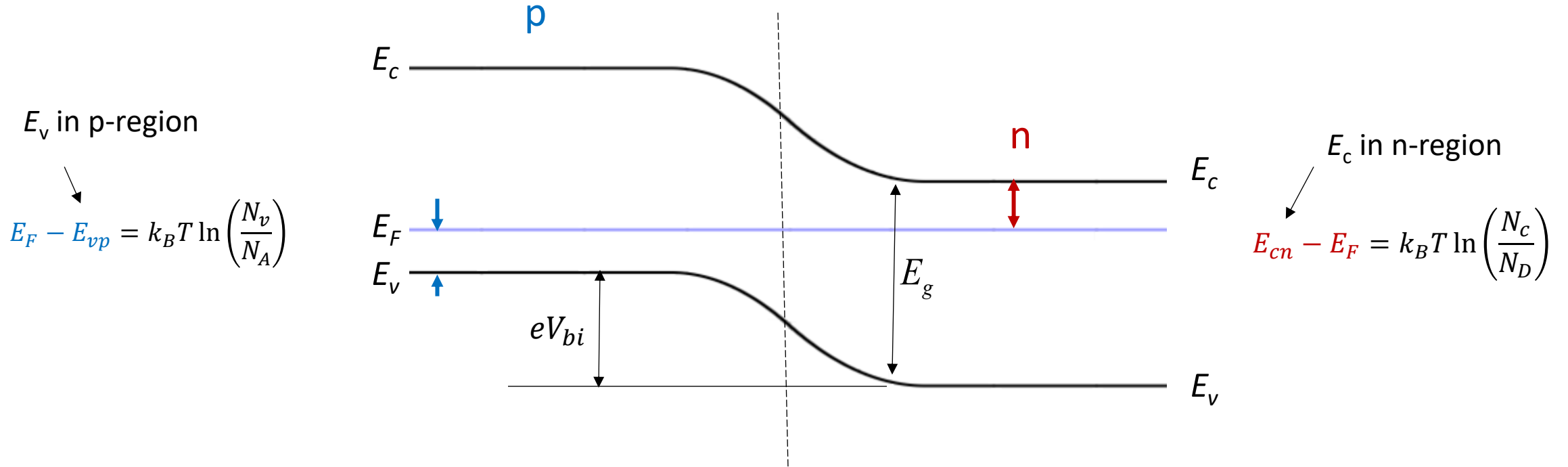


7

## pn junctions

# Built-in voltage $V_{bi}$



$$eV_{bi} = E_g - k_B T \ln \left( \frac{N_c}{N_{D,n} - N_{A,n}} \right) - k_B T \ln \left( \frac{N_v}{N_{A,p} - N_{D,p}} \right)$$

$$eV_{bi} = E_g - k_B T \ln \left( \frac{N_c N_v}{(N_{D,n} - N_{A,n})(N_{A,p} - N_{D,p})} \right)$$

$$eV_{bi} = E_g - k_B T \ln \left( \frac{N_c N_v}{(N_{D,n} - N_{A,n})(N_{A,p} - N_{D,p})} \right)$$

$$n_i^2 = N_v N_c \exp \left( \frac{-E_g}{k_B T} \right)$$

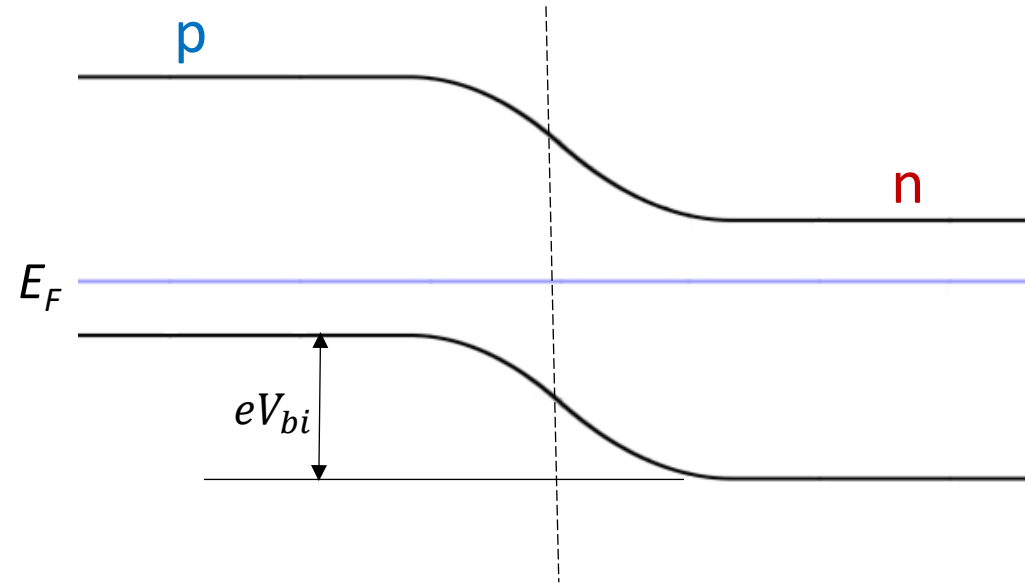
$$E_g = -k_B T \ln \left( \frac{n_i^2}{N_v N_c} \right)$$

$$eV_{bi} = k_B T \ln \left( \frac{(N_{D,n} - N_{A,n})(N_{A,p} - N_{D,p})}{n_i^2} \right)$$

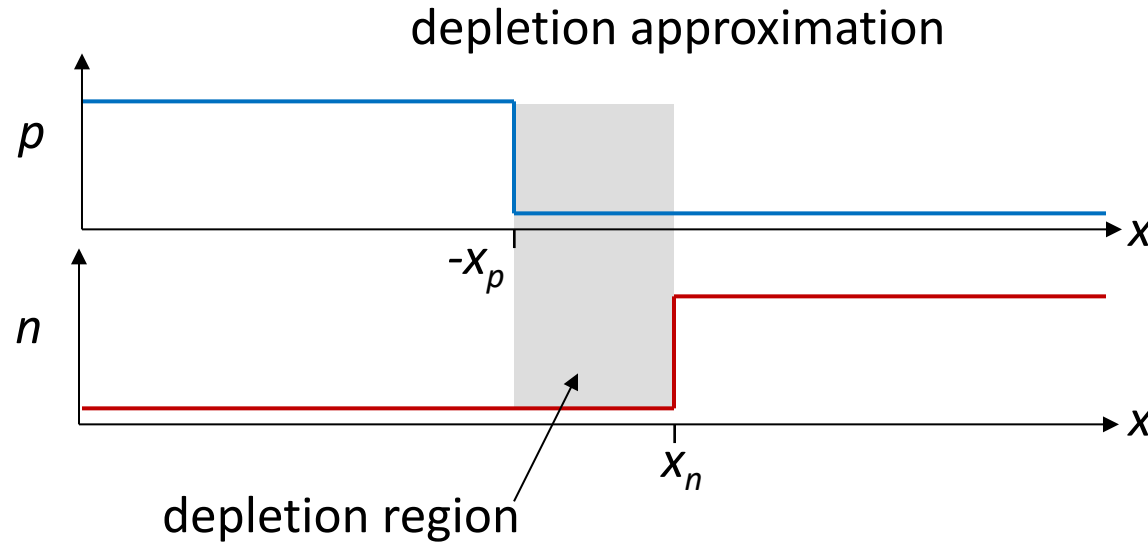
for  $N_{D,n} - N_{A,n} = N_D$  and  $N_{A,p} - N_{D,p} = N_A$

$$eV_{bi} = k_B T \ln \left( \frac{N_D N_A}{n_i^2} \right)$$

# p and n profiles

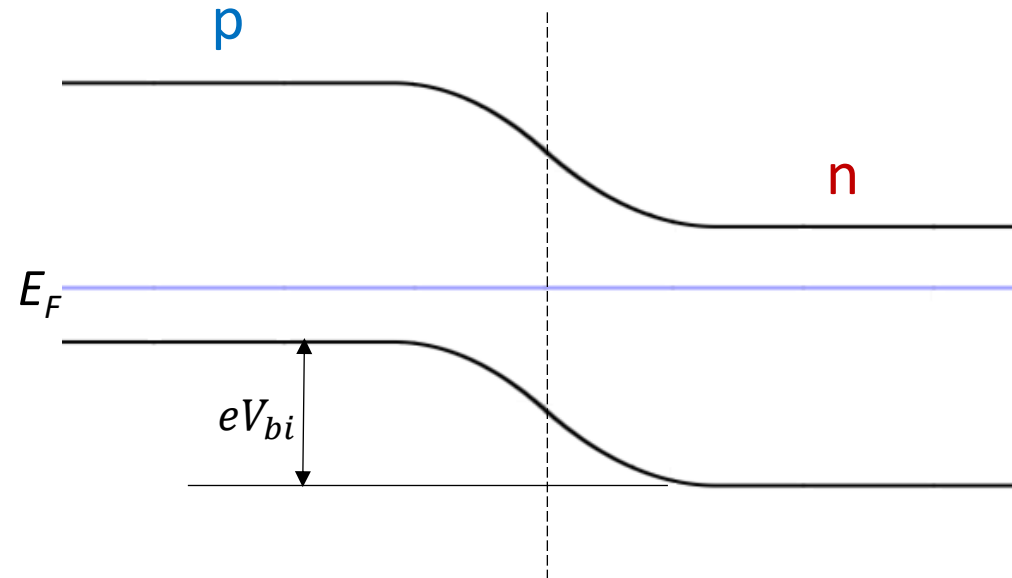


$$p = N_v \exp\left(\frac{E_v - E_F}{k_B T}\right)$$

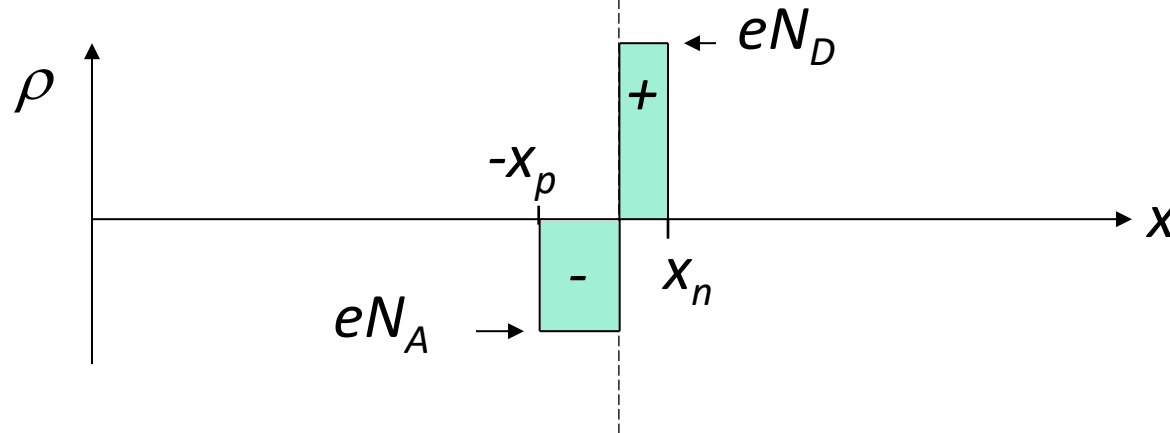


$$n = N_c \exp\left(\frac{E_F - E_c}{k_B T}\right)$$

# space charge



exposed ionized dopants



$$N_A x_p = N_D x_n$$

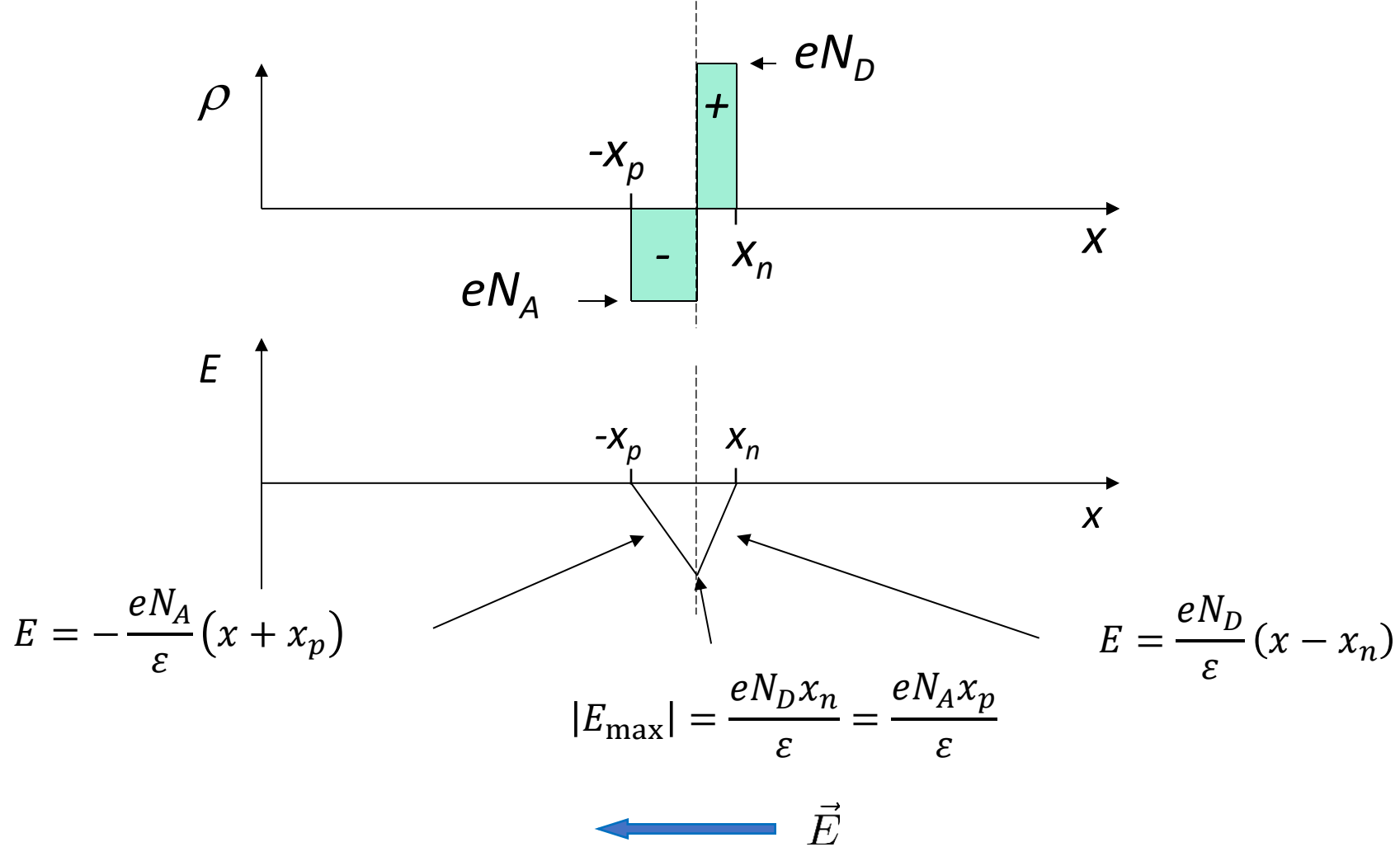
# electric field

Gauss's law

$$\nabla \cdot \vec{E} = \frac{\rho}{\epsilon}$$

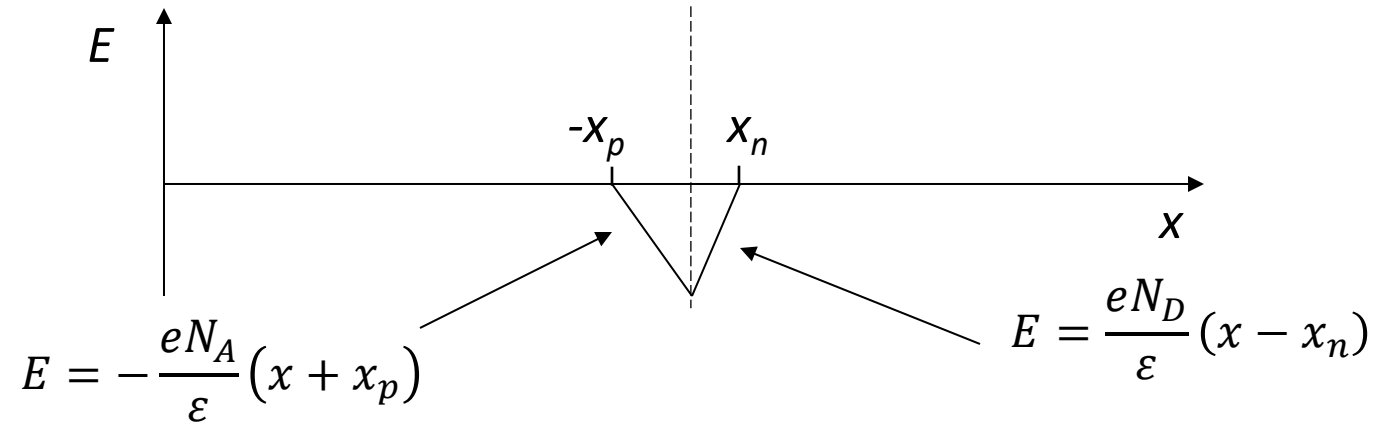
in 1-D is

$$\frac{dE}{dx} = \frac{\rho}{\epsilon}$$



$E$  pushes the holes towards  $p$  and the electrons towards  $n$

# electrostatic potential



$$\frac{dV}{dx} = -E$$

$$-x_p > x > 0$$

$$0 > x > x_n$$

$$V = \frac{eN_A}{\epsilon} \left( \frac{x^2}{2} + xx_p \right)$$

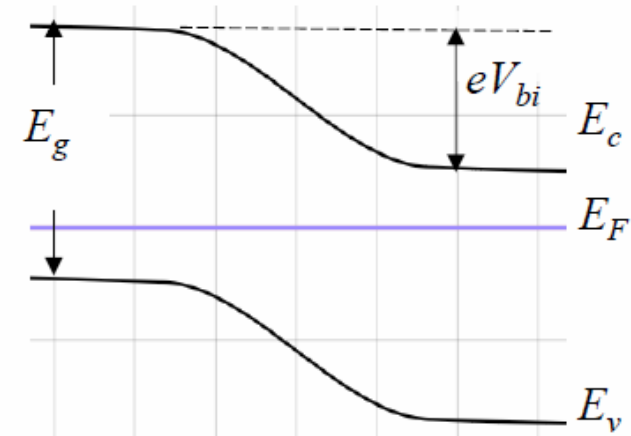
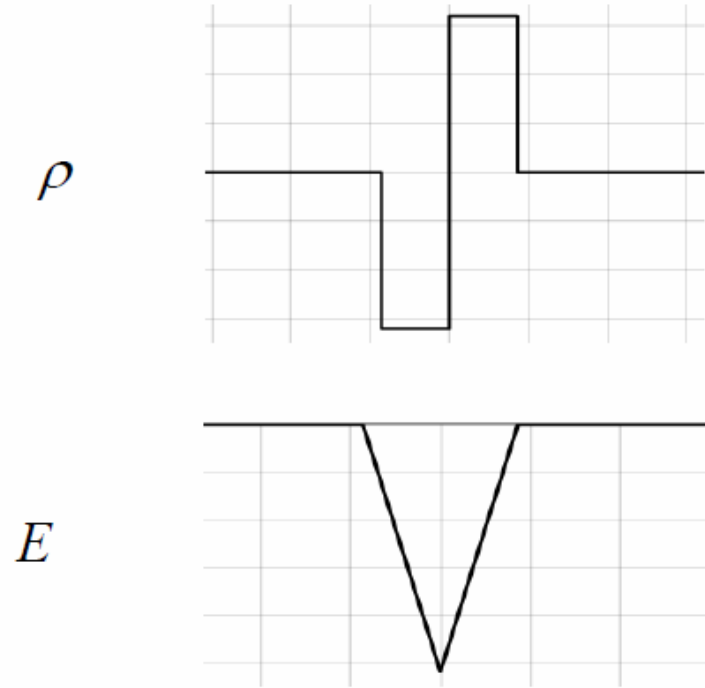
$$V = \frac{-eN_D}{\epsilon} \left( \frac{x^2}{2} - xx_n \right)$$

$$V(-x_p) = \frac{-eN_A}{2\epsilon} x_p^2 \quad V(0) = 0 \quad V(x_n) = \frac{eN_D}{2\epsilon} x_n^2$$

# abrupt pn junction

$$V_{bi} = \frac{k_B T}{e} \ln \left( \frac{N_D N_A}{n_i^2} \right)$$
$$= \frac{e N_A x_p^2}{2\epsilon} + \frac{e N_D x_n^2}{2\epsilon}$$

<https://lampz.tugraz.at/~hadley/psd/L6/abrupt.html>





## Depletion width

$$V_{bi} = \frac{k_B T}{e} \ln \left( \frac{N_D N_A}{n_i^2} \right) = \frac{e N_A x_p^2}{2\epsilon} + \frac{e N_D x_n^2}{2\epsilon}$$

$$N_A x_p = N_D x_n = N_D (W - x_p) = N_A (W - x_n)$$

$$x_p = \frac{N_D W}{N_A + N_D}$$

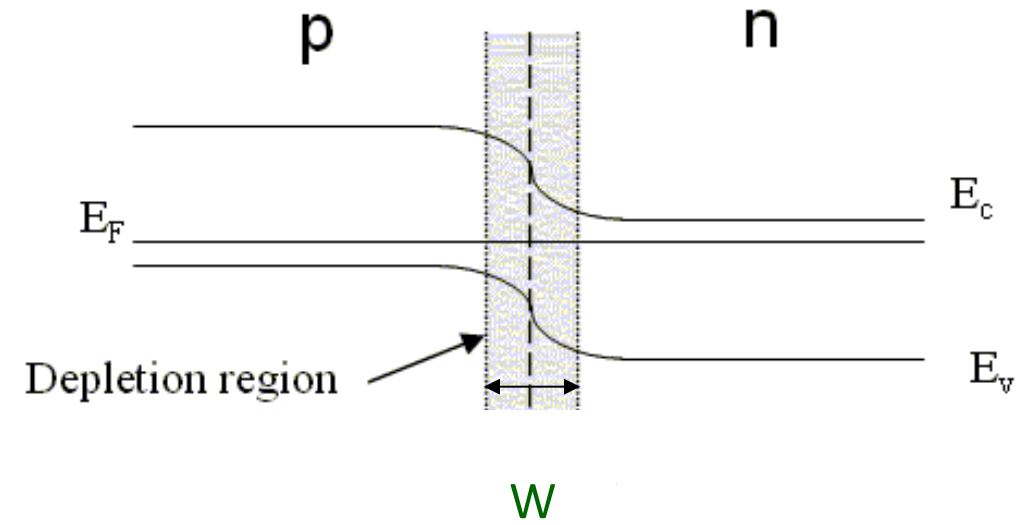
$$x_n = \frac{N_A W}{N_A + N_D}$$

$$V_{bi} = \frac{e}{2\epsilon} \frac{N_D N_A}{N_D + N_A} W^2$$

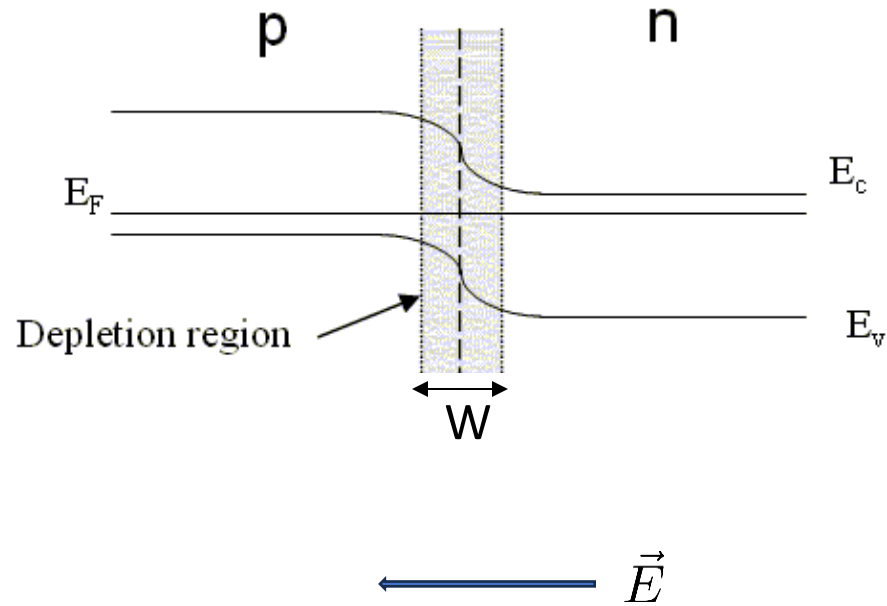
$$W = \sqrt{\frac{2\epsilon (N_D + N_A) V_{bi}}{e N_D N_A}}$$

light doping:

wide depletion width



## Depletion width



$$V_{bi} \sim 1V$$

$$W \sim 10 \text{ nm} - 10 \mu\text{m}$$

$$E_{max} \sim 10^4 \text{ V/cm}$$

The electric field pushes the electrons towards the n-region and the holes towards the p-region.

Diffusion sends electrons towards the p-region and holes towards the n-region.

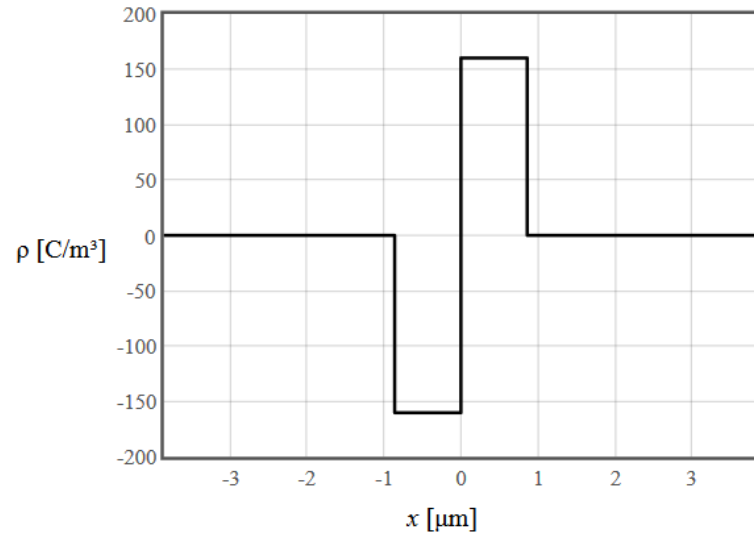
## Abrupt pn junctions in the depletion approximation

In an abrupt pn junction, the doping changes abruptly from p to n. It is common to solve for the band bending, the local electric field, the carrier concentration profiles, and the local conductivity in the depletion approximation. In this approximation it is assumed that there is a depletion width  $W$  around the transition from p to n where the charge carrier densities are negligible. Outside the depletion width the charge carrier densities are equal to the doping densities so that the semiconductor is electrically neutral outside the depletion width. Using this approximation it is possible to calculate the important properties of the pn junction.

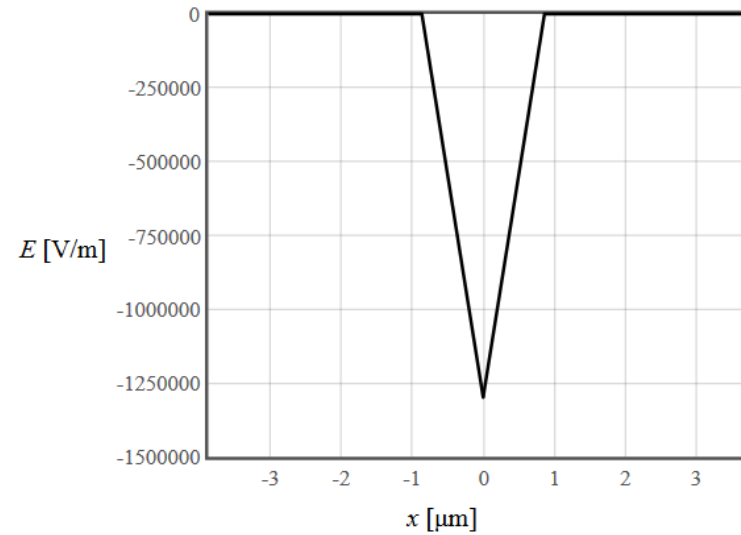
$N_A =$ <input type="text" value="1E15"/> /cm <sup>3</sup>	$N_D =$ <input type="text" value="1E15"/> /cm <sup>3</sup>	$E_g =$ <input type="text" value="1.166-4.73E-4*T*(T+636)"/> eV
$N_v(300) =$ <input type="text" value="9.84E18"/> /cm <sup>3</sup>	$N_c(300) =$ <input type="text" value="2.78E19"/> /cm <sup>3</sup>	$\epsilon_r =$ <input type="text" value="12"/> $T =$ <input type="text" value="300"/> K
$\mu_p =$ <input type="text" value="480"/> cm <sup>2</sup> /V s	$\mu_n =$ <input type="text" value="1350"/> cm <sup>2</sup> /V s	$\tau_p =$ <input type="text" value="1E-10"/> s $\tau_n =$ <input type="text" value="1E-10"/> s
$V =$ <input type="text" value="-0.5"/> V		<input type="button" value="Submit"/>

$E_g = 1.12$  eV     $W = 1.72$   $\mu\text{m}$      $x_p = -0.861$   $\mu\text{m}$      $x_n = 0.861$   $\mu\text{m}$      $V_{bi} = 0.618$  V     $C_j = 6.17$  nF/cm<sup>2</sup>  
 $D_p = 12.4$  cm<sup>2</sup>/s     $D_n = 34.9$  cm<sup>2</sup>/s     $L_p = 0.352$   $\mu\text{m}$      $L_n = 0.591$   $\mu\text{m}$

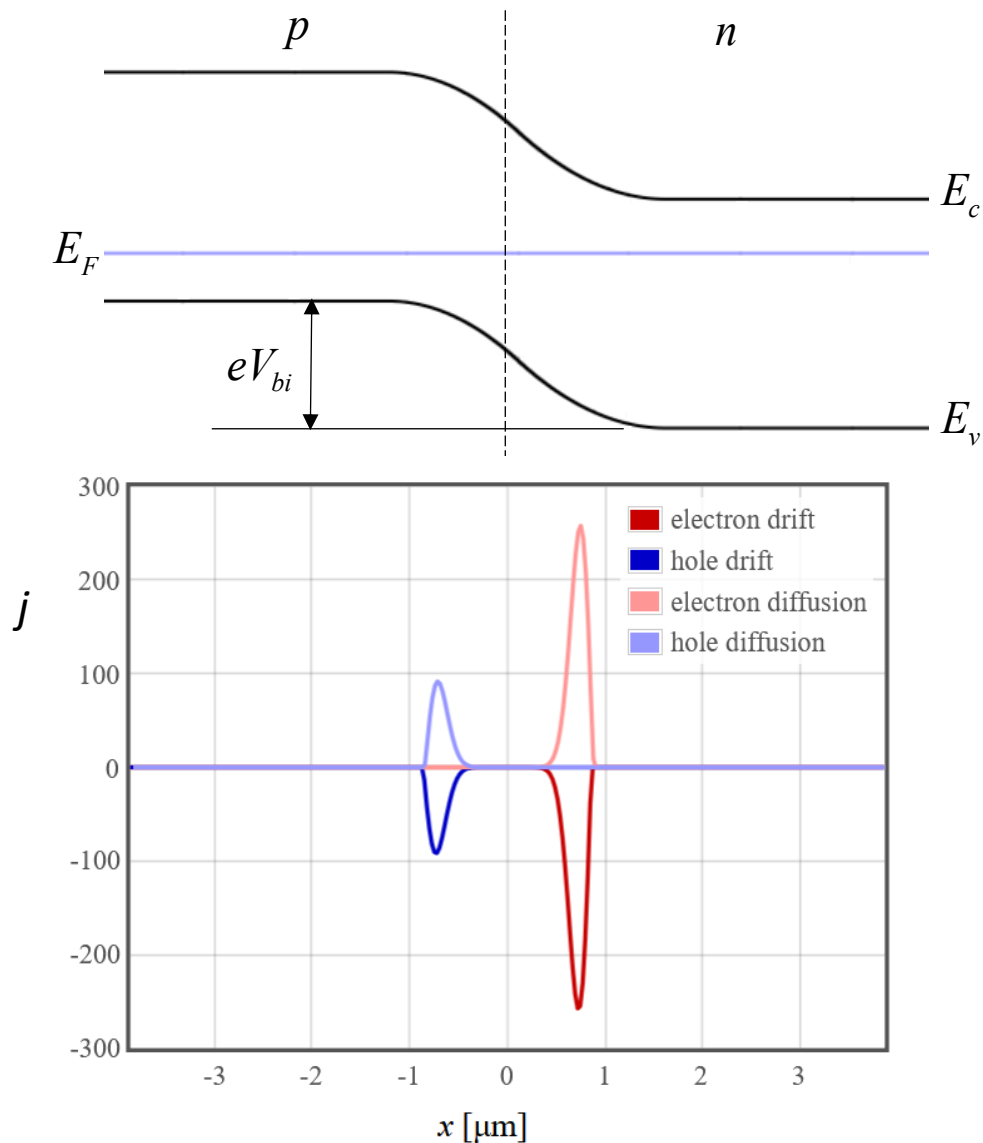
Charge density



Electric field



# Drift and diffusion



$$\vec{j}_n = en\mu_n\vec{E} + eD_n\nabla n$$

$$n = N_c \exp\left(\frac{E_F - E_c}{k_B T}\right)$$

$$\nabla n = -\frac{\nabla E_c}{k_B T} N_c \exp\left(\frac{E_F - E_c}{k_B T}\right) = -\frac{\nabla E_c}{k_B T} n$$

$$e\vec{E} = \nabla E_c$$

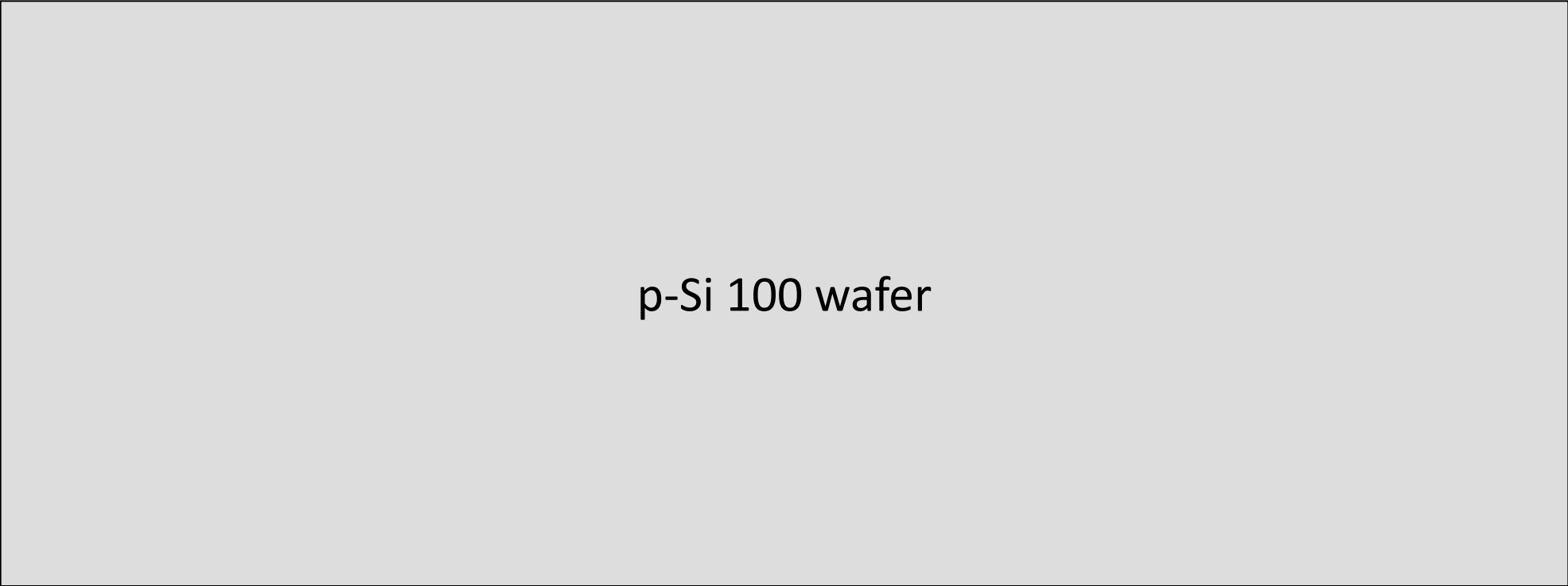
$$\vec{j}_n = n\nabla E_c \left( \mu_n - \frac{eD_n}{k_B T} \right)$$

↑  
Einstein relation

If the  $E_F$  is constant,  $j = 0$ .

# diode fabrication

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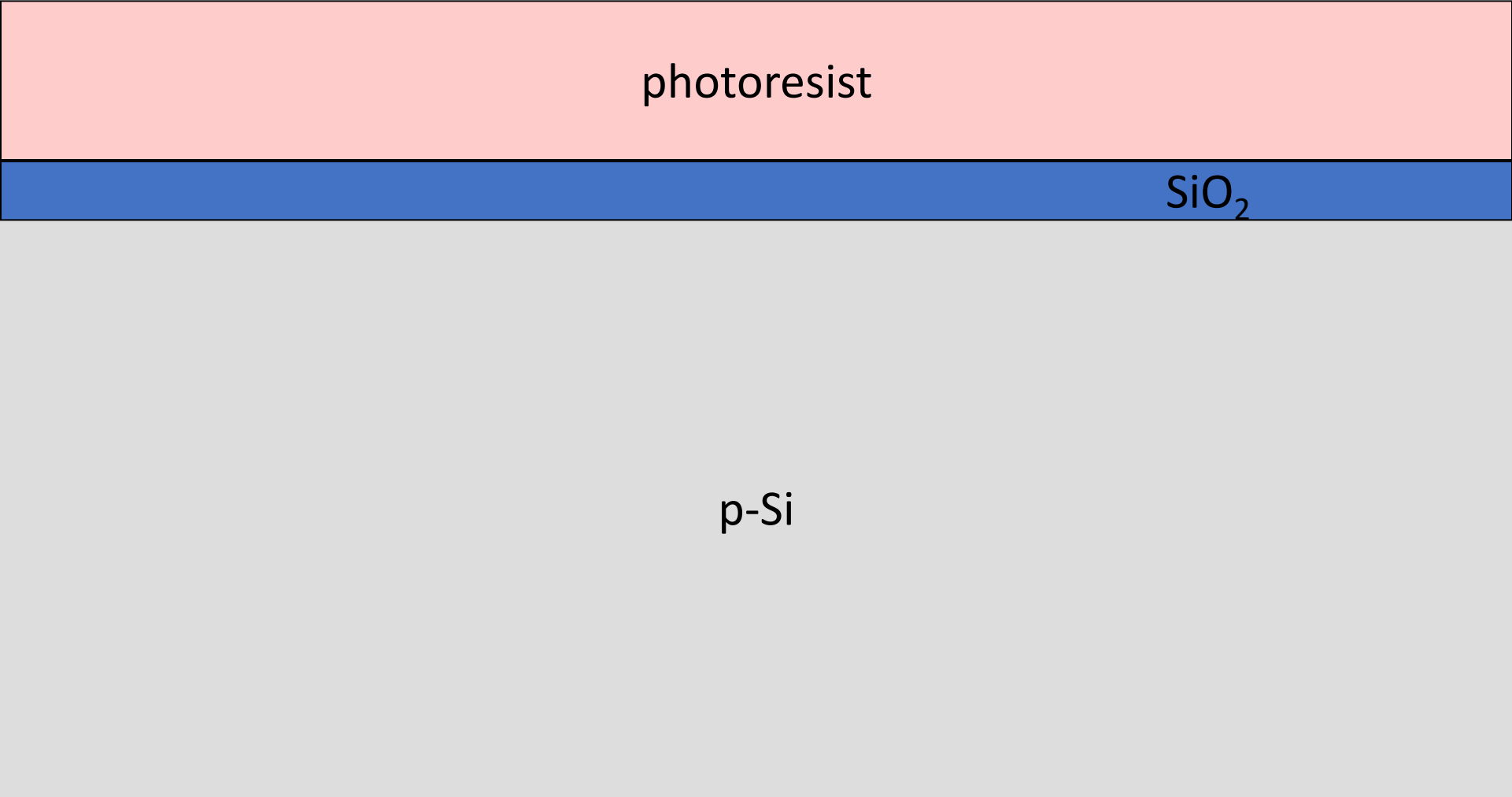
p-Si 100 wafer

CVD oxide

SiO<sub>2</sub>



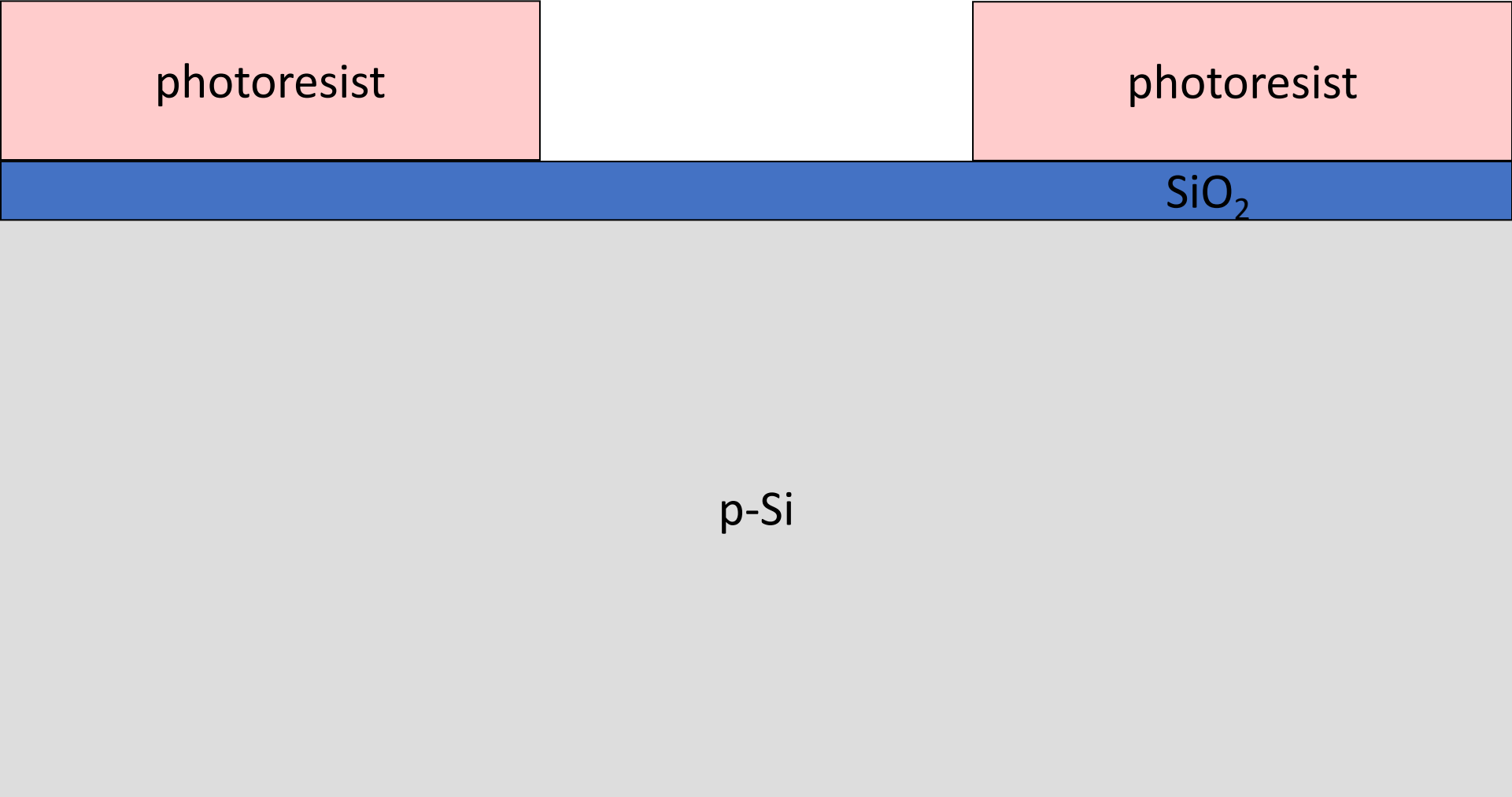
p-Si



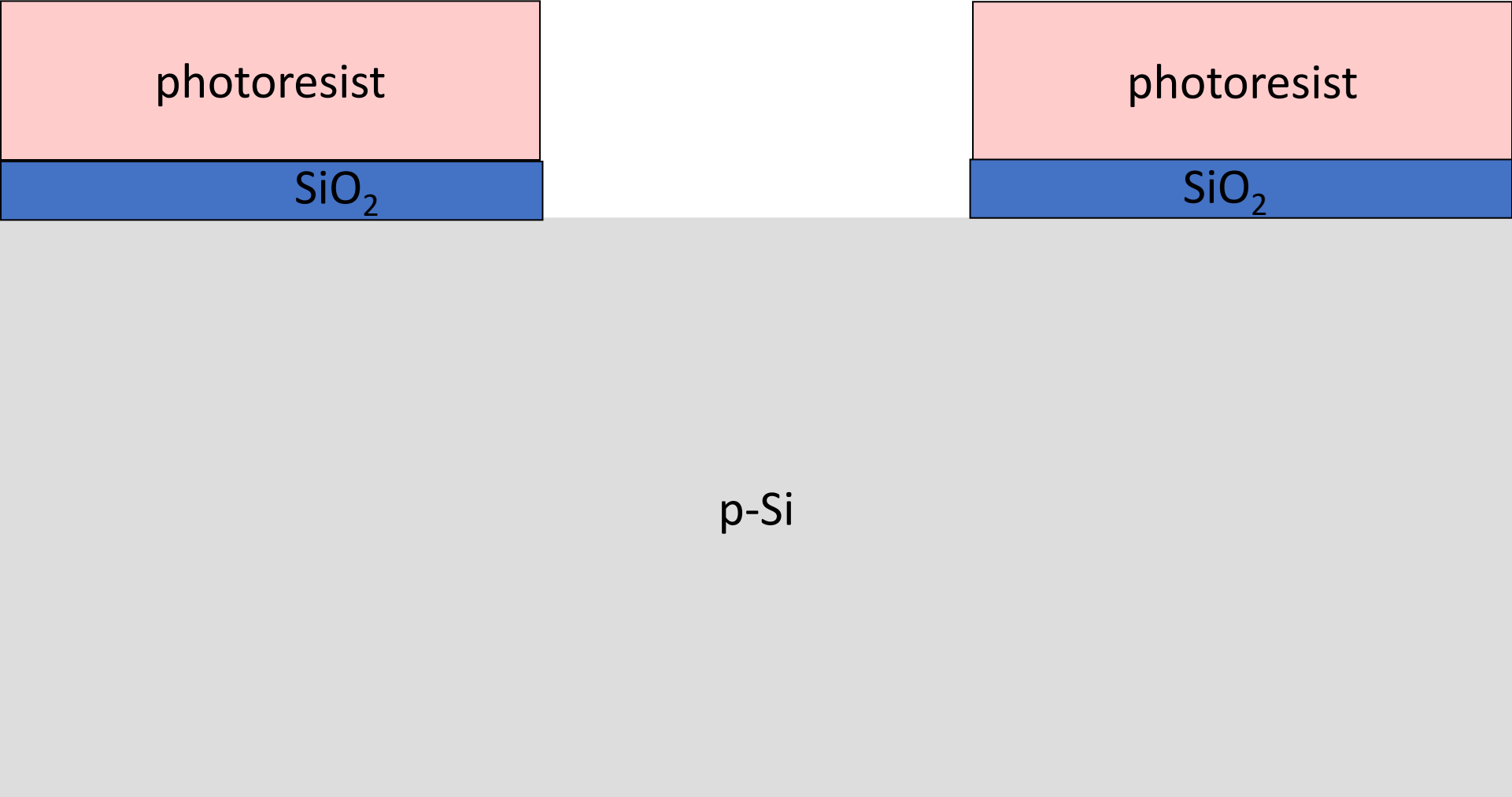
photoresist

SiO<sub>2</sub>

p-Si





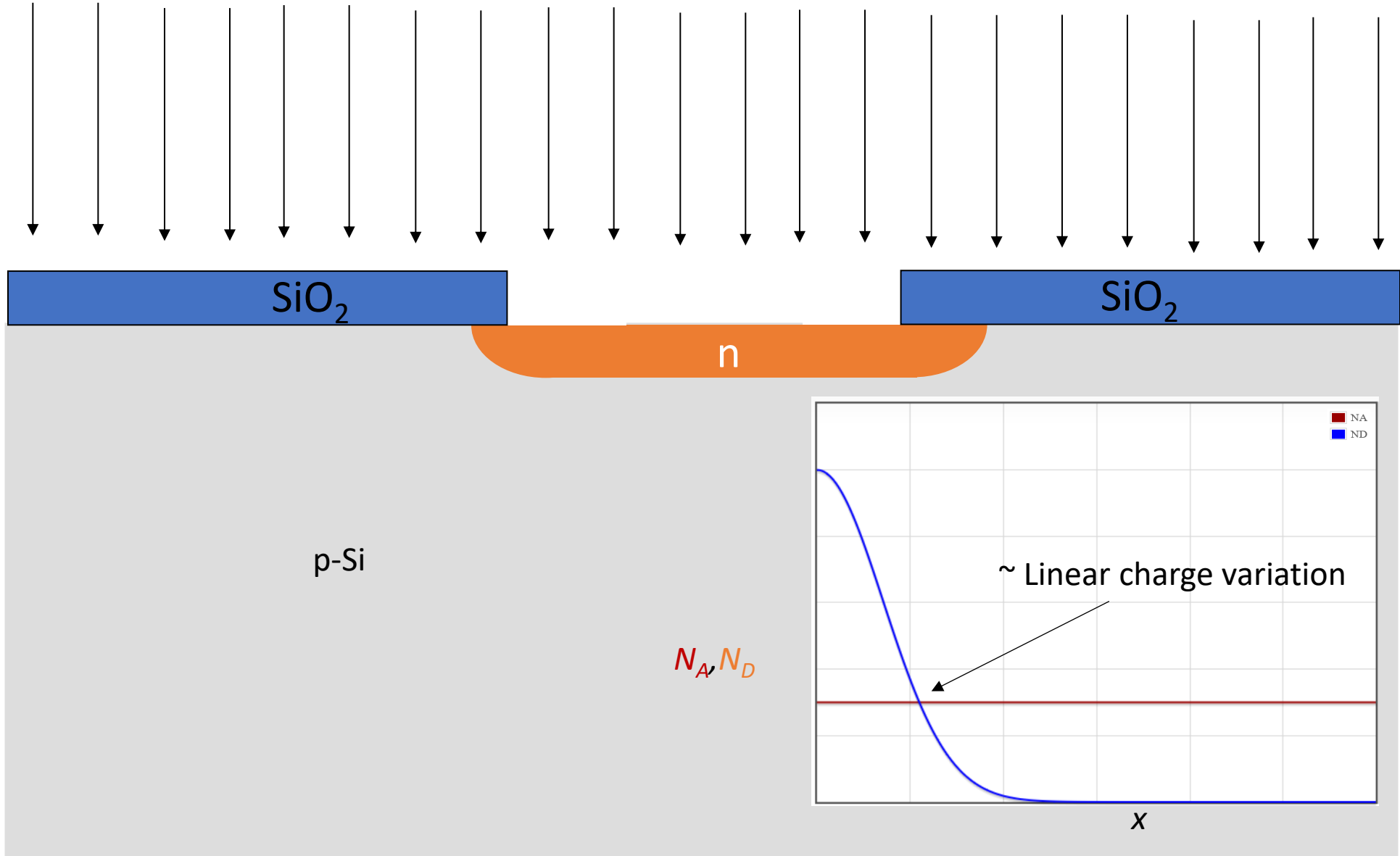


SiO<sub>2</sub>

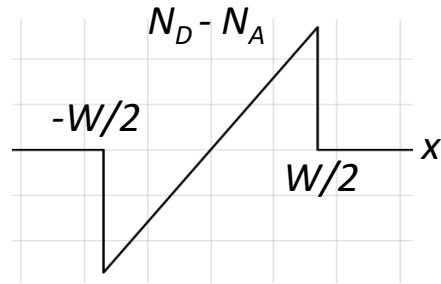
SiO<sub>2</sub>

p-Si

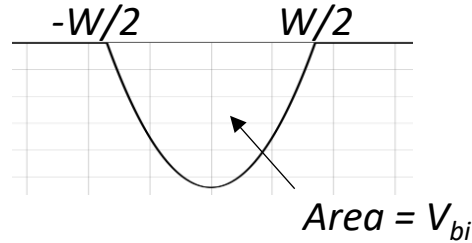
# Diffuse or Implant



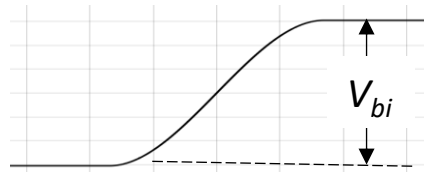
# linearly graded junction



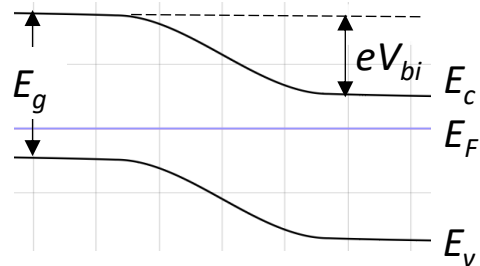
$$\rho = e(N_D(x) - N_A(x)) = eax$$



$$E = \int \frac{\rho}{\epsilon} dx = \frac{-ea}{2\epsilon} \left( \left( \frac{W}{2} \right)^2 - x^2 \right) \quad E_{max} = \frac{-eaW^2}{8\epsilon}$$



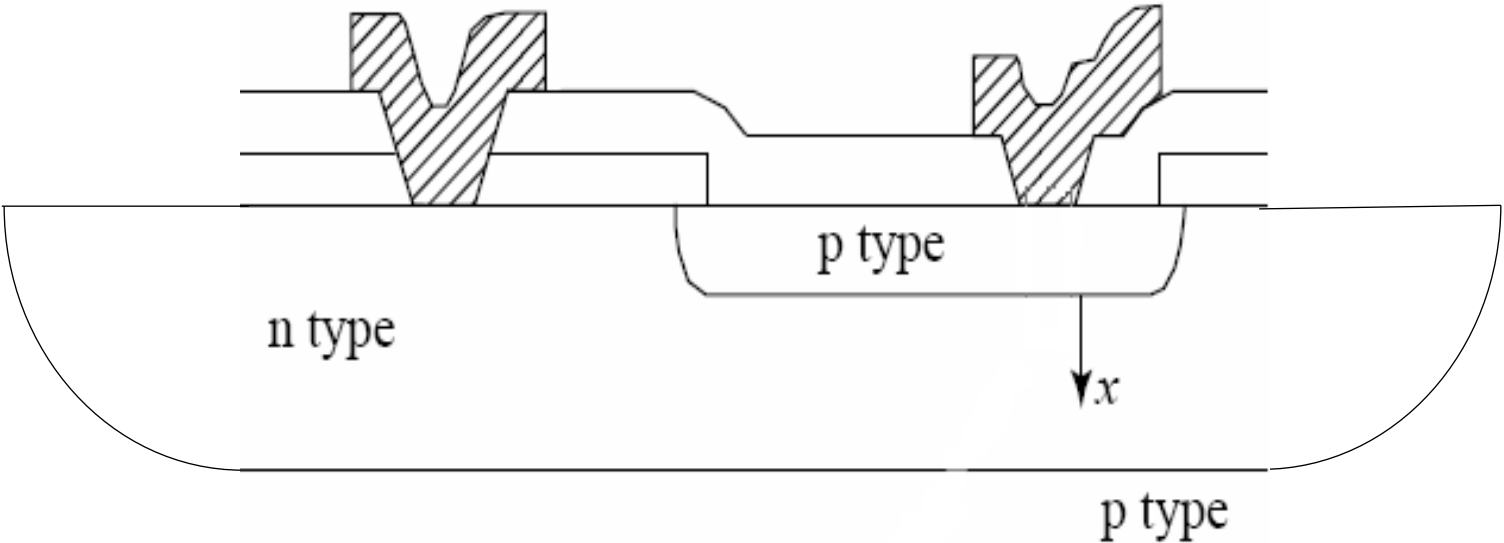
$$V = \int E dx = \frac{ea}{2\epsilon} \left( \left( \frac{W}{2} \right)^2 x - \frac{x^3}{3} \right)$$



$$V_{bi} = \frac{eaW^3}{12\epsilon}$$

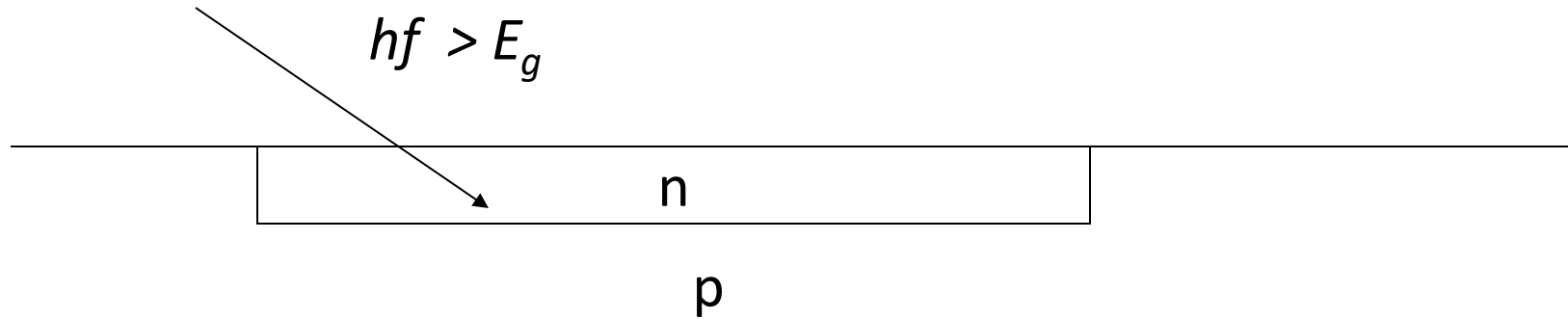
# Isolation

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## solar cell

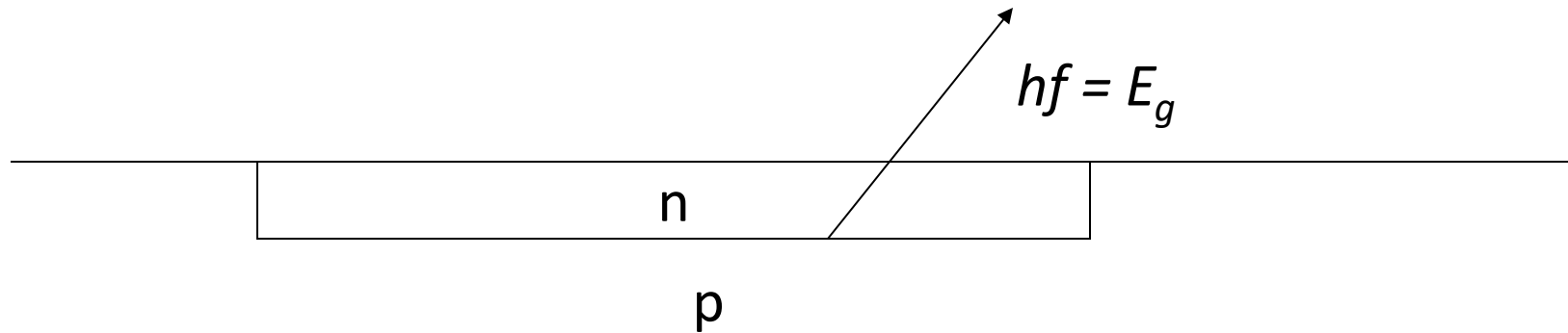
---



Light creates an electron-hole pair in the depletion region. The electric field sweeps the electrons towards the n-region and the holes towards the p-region.

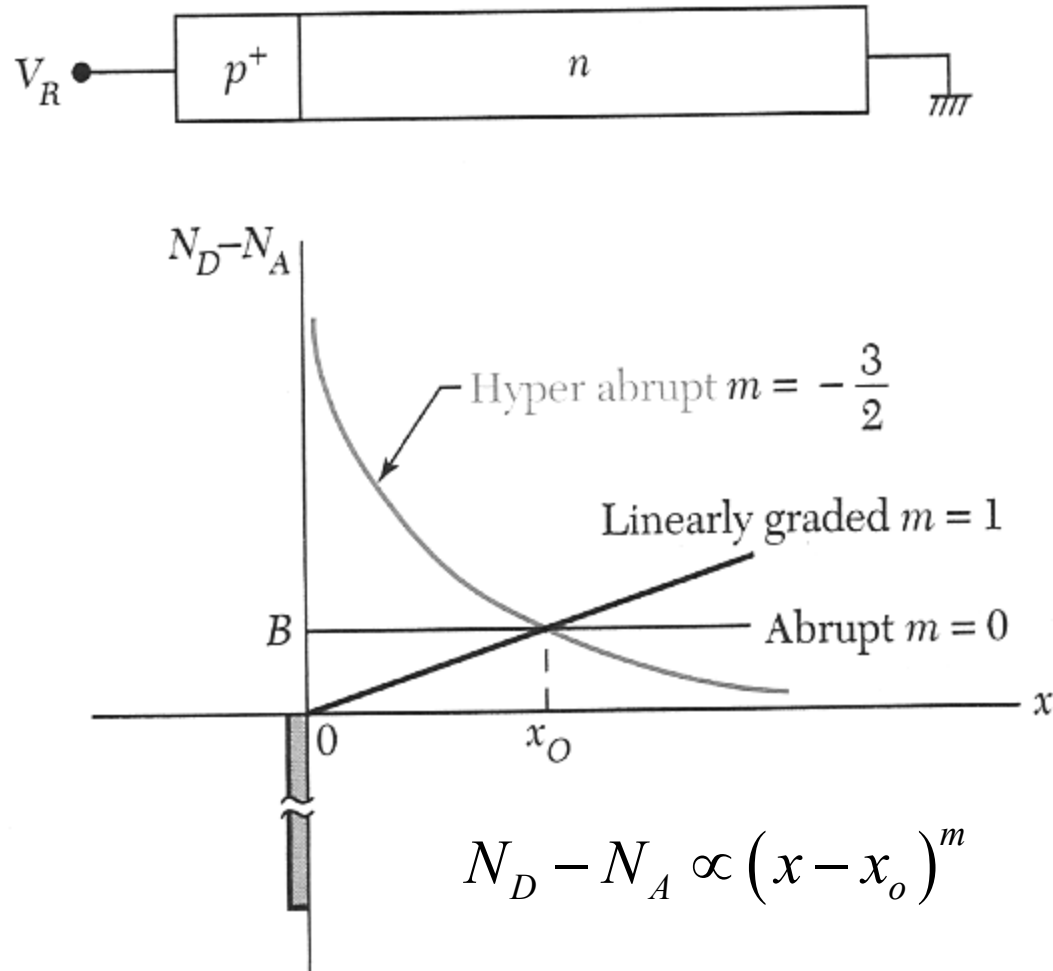
## Light emitting diode

---



Electrons and holes are injected into the depletion region by forward biasing the junction. The electrons fall in the holes. For direct bandgap semiconductors, photons are emitted. For indirect bandgap semiconductors, phonons are emitted.

# Varactor



$$C_j \propto (V_{bi} + V_R)^{-n}$$

abrupt:  $n = 1/2$

linearly graded:  $n = 1/3$

$$n = 1/(m+2)$$





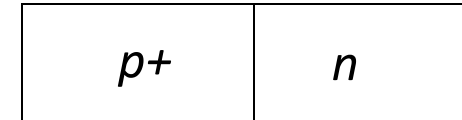
## Capacitance-voltage characteristics

---

specific capacitance  $C_j = \frac{\epsilon}{W} \text{ F m}^{-2}$

abrupt junction:  $W = \frac{\epsilon}{C_j} = \sqrt{\frac{2\epsilon(N_D + N_A)(V_{bi} - V)}{eN_D N_A}}$

a one-sided abrupt junction in reverse bias:



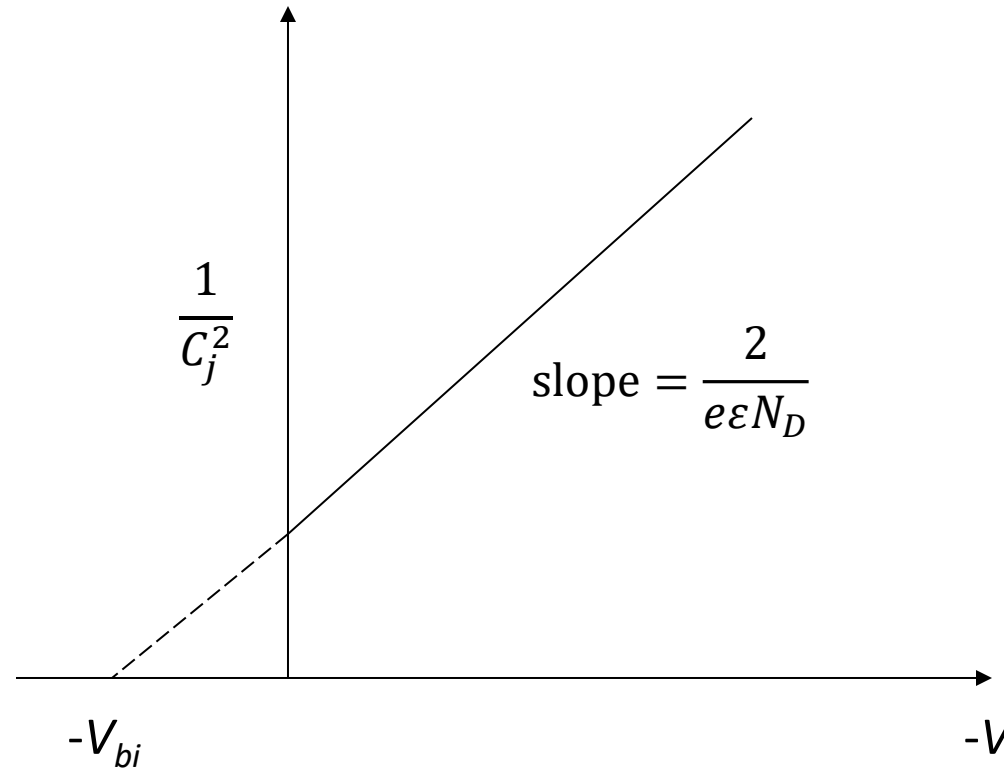
$$\frac{1}{C_j^2} = \frac{2(V_{bi} - V)}{e\epsilon N_D}$$

# Capacitance-voltage characteristics

a one-sided  
abrupt junction in  
reverse bias:

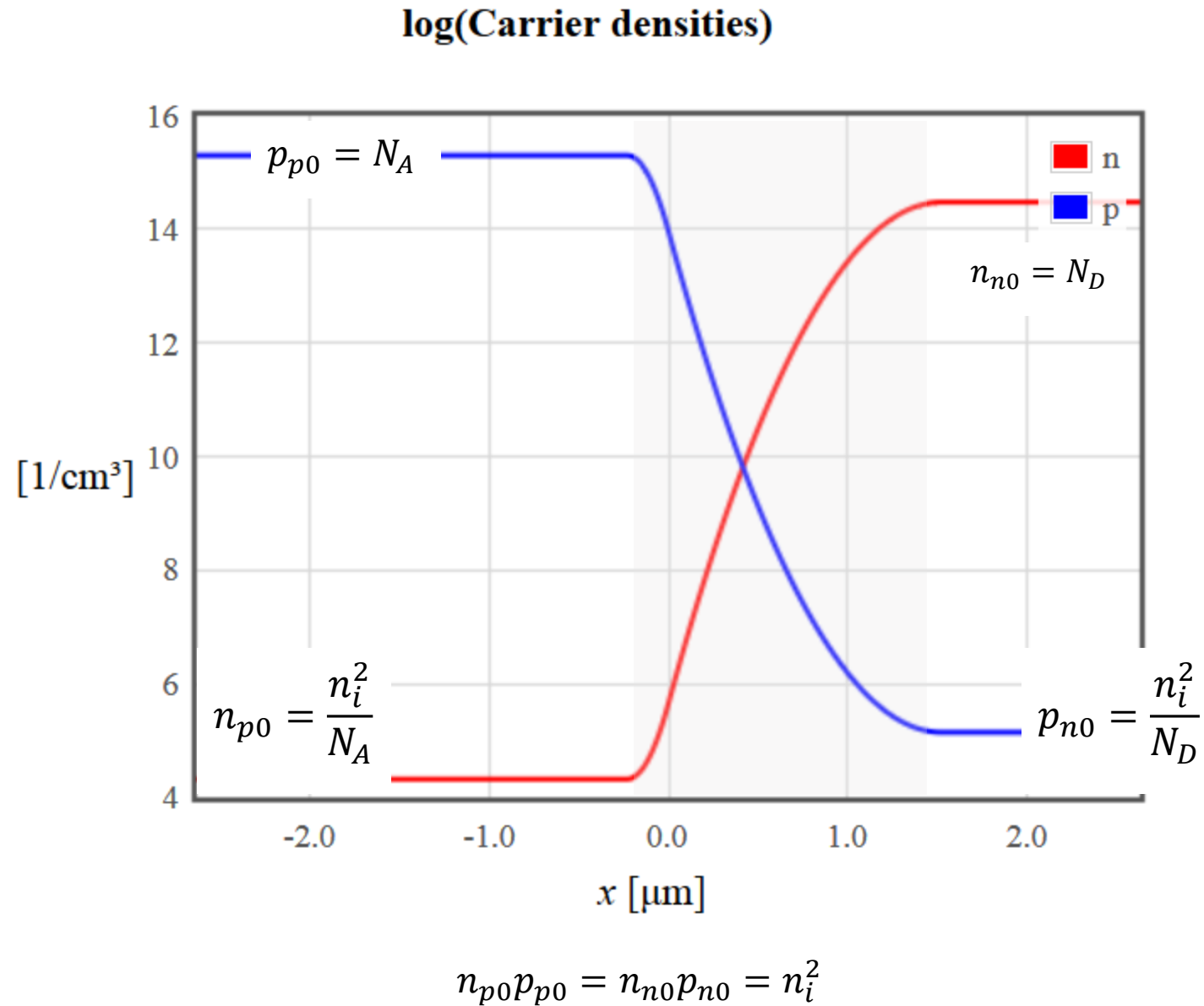
$p+$	$n$
------	-----

$$\frac{1}{C_j^2} = \frac{2(V_{bi} - V)}{e\epsilon N_D}$$



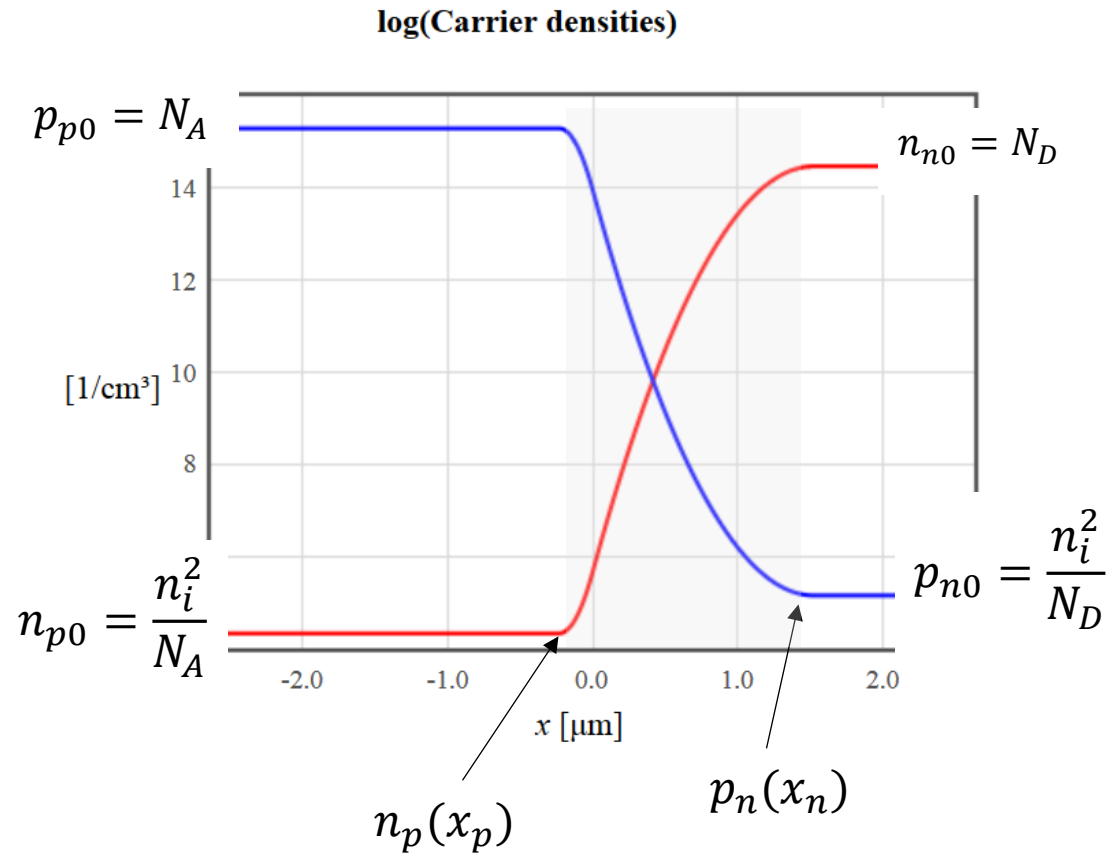
slope gives impurity concentration and the intercept gives  $V_{bi}$

# equilibrium concentrations, $V = 0$



## bias voltage, $V = 0$

$$eV_{bi} = k_B T \ln\left(\frac{N_D N_A}{n_i^2}\right) = k_B T \ln\left(\frac{N_D}{n_{p0}}\right) = k_B T \ln\left(\frac{N_A}{p_{n0}}\right)$$



$$n_{p0} p_{p0} = n_{n0} p_{n0} = n_i^2$$

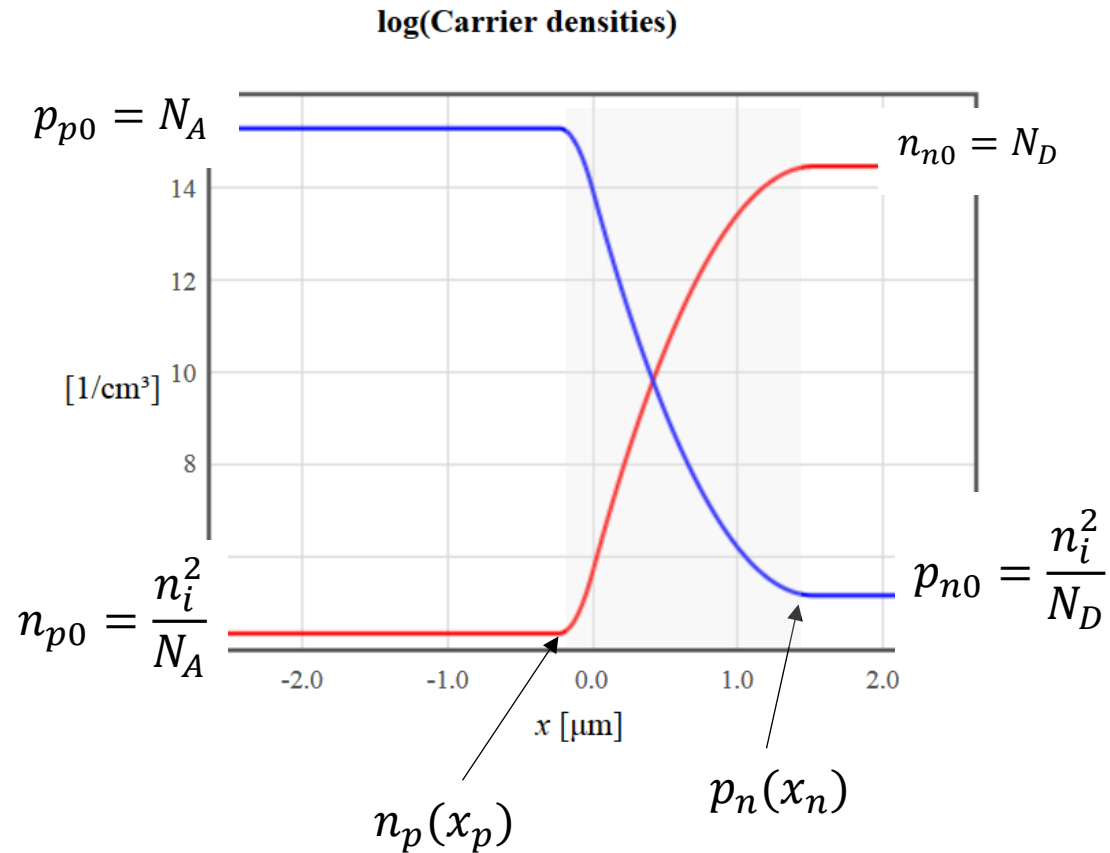
$$V = 0$$

$$n_{p0} = N_D \exp\left(\frac{-eV_{bi}}{k_B T}\right)$$

$$p_{n0} = N_A \exp\left(\frac{-eV_{bi}}{k_B T}\right)$$

## bias voltage, $V \neq 0$

$$eV_{bi} = k_B T \ln\left(\frac{N_D N_A}{n_i^2}\right) = k_B T \ln\left(\frac{N_D}{n_{p0}}\right) = k_B T \ln\left(\frac{N_A}{p_{n0}}\right)$$



$$n_{p0} p_{p0} = n_{n0} p_{n0} = n_i^2$$

$V = 0$

$$n_{p0} = N_D \exp\left(\frac{-eV_{bi}}{k_B T}\right)$$

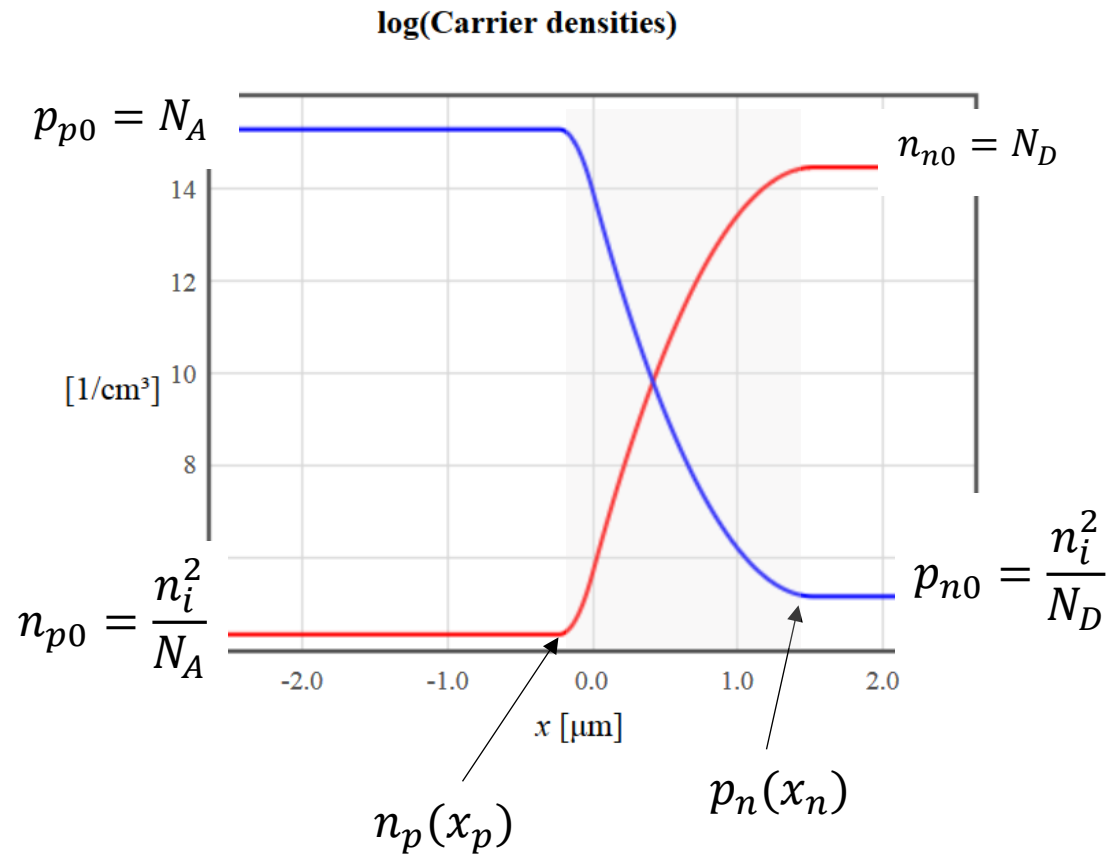
$$p_{n0} = N_A \exp\left(\frac{-eV_{bi}}{k_B T}\right)$$

$V \neq 0$

$$n_p(x_p) = N_D \exp\left(\frac{-e(V_{bi} - V)}{k_B T}\right)$$

$$p_n(x_n) = N_A \exp\left(\frac{-e(V_{bi} - V)}{k_B T}\right)$$

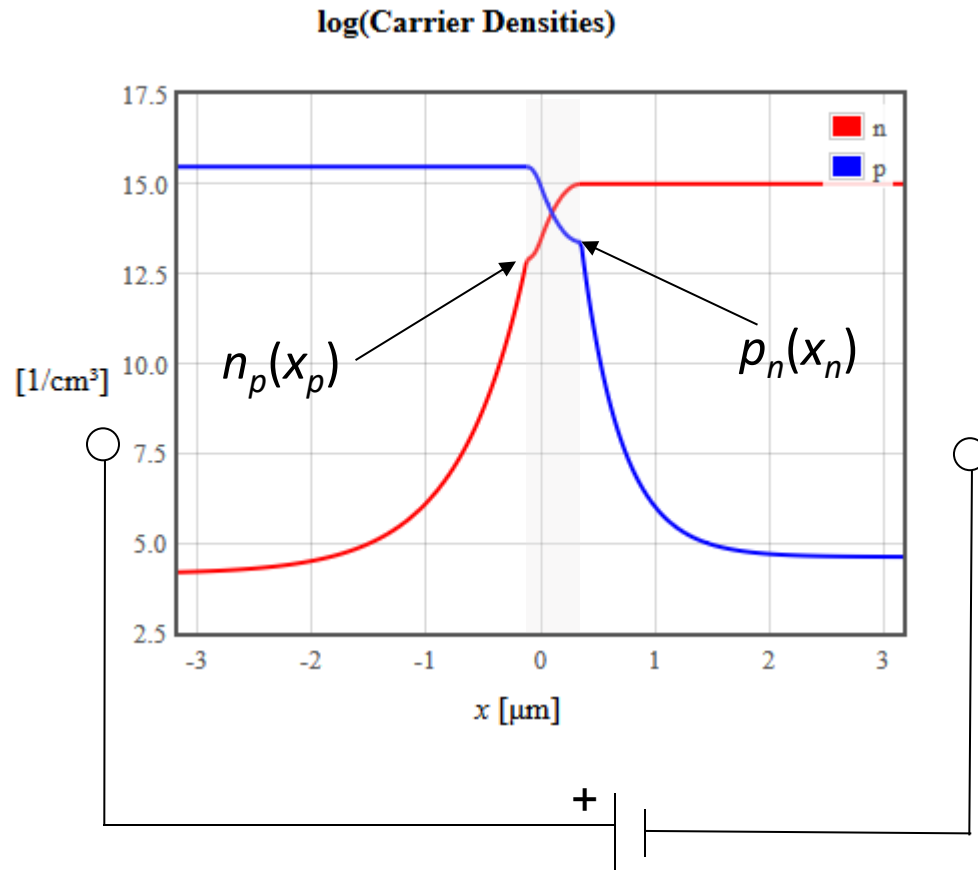
## bias voltage, $V \neq 0$



$$n_p(x_p) = N_D \exp\left(\frac{-e(V_{bi} - V)}{k_B T}\right) = n_{p0} \exp\left(\frac{eV}{k_B T}\right)$$

$$p_n(x_n) = N_A \exp\left(\frac{-e(V_{bi} - V)}{k_B T}\right) = p_{n0} \exp\left(\frac{eV}{k_B T}\right)$$

## forward bias, $V > 0$

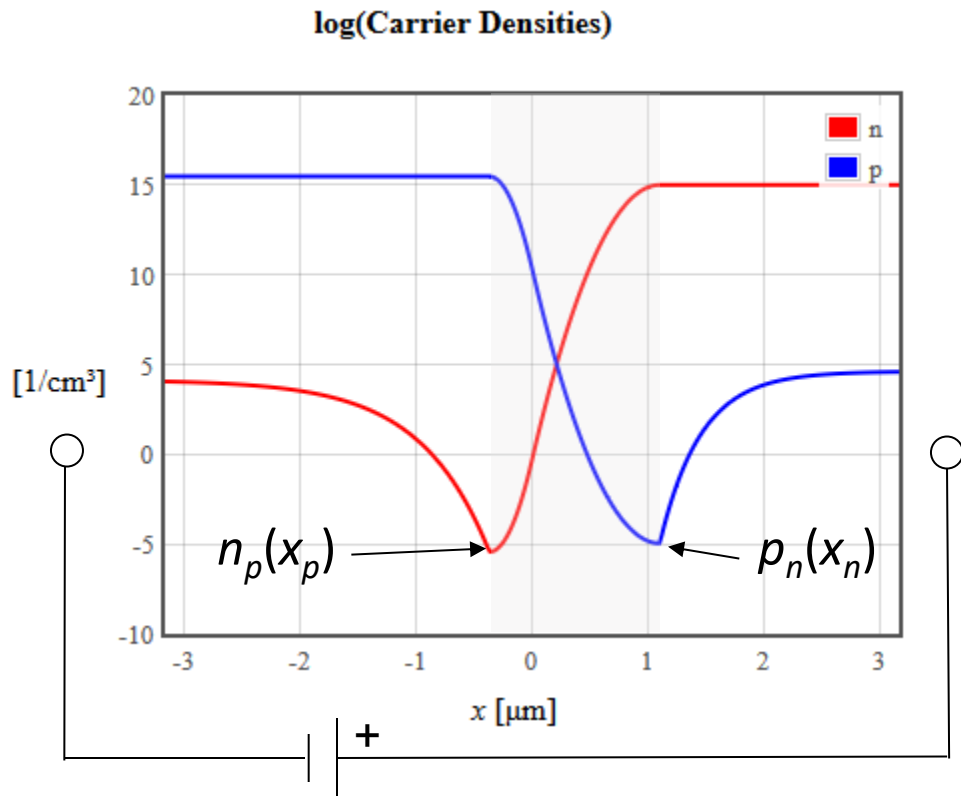


Electrons and holes are driven towards the junction.  
The depletion region becomes narrower

$$n_p(x_p) = n_{p0} \exp\left(\frac{eV}{k_B T}\right)$$
$$p_n(x_n) = p_{n0} \exp\left(\frac{eV}{k_B T}\right)$$

Minority electrons are injected into the p-region  
Minority holes are injected into the n-region

## reverse bias, $V < 0$



Electrons and holes are driven away from the junction.

The depletion region becomes wider

$$n_p(x_p) = n_{p0} \exp\left(\frac{eV}{k_B T}\right)$$

$$p_n(x_n) = p_{n0} \exp\left(\frac{eV}{k_B T}\right)$$

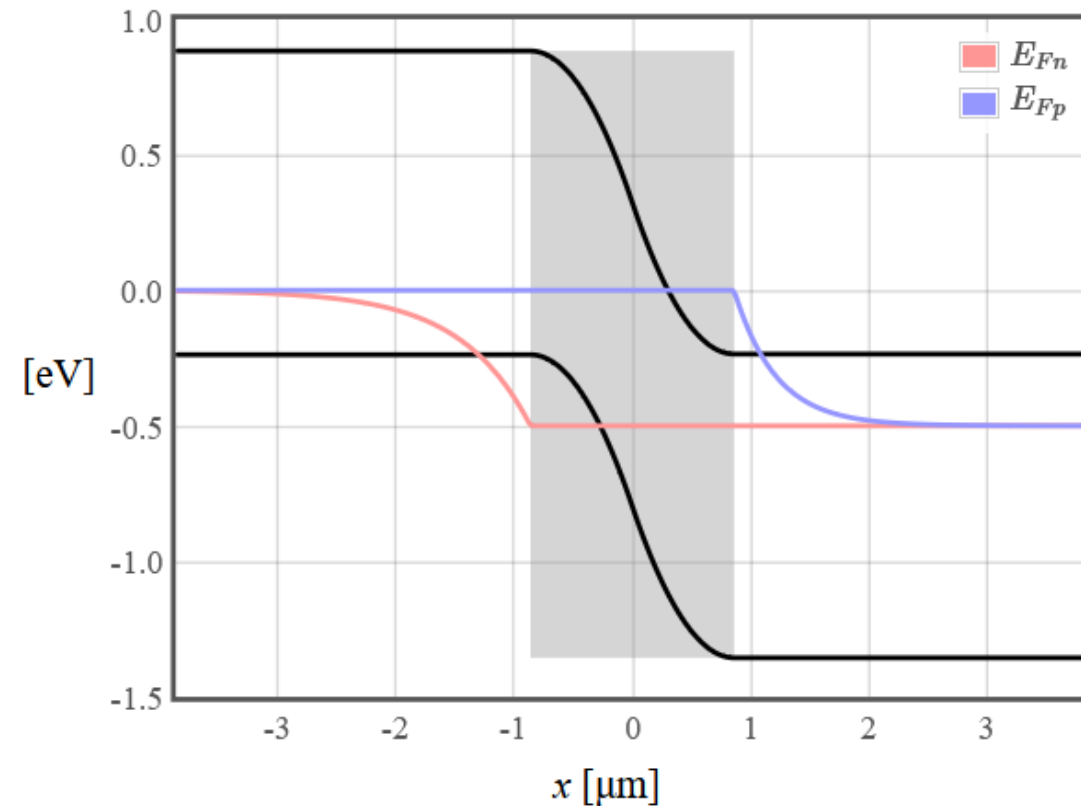
Minority electrons are extracted from the p-region by the electric field  
Minority holes are extracted from the n-region by the electric field



# Quasi Fermi level

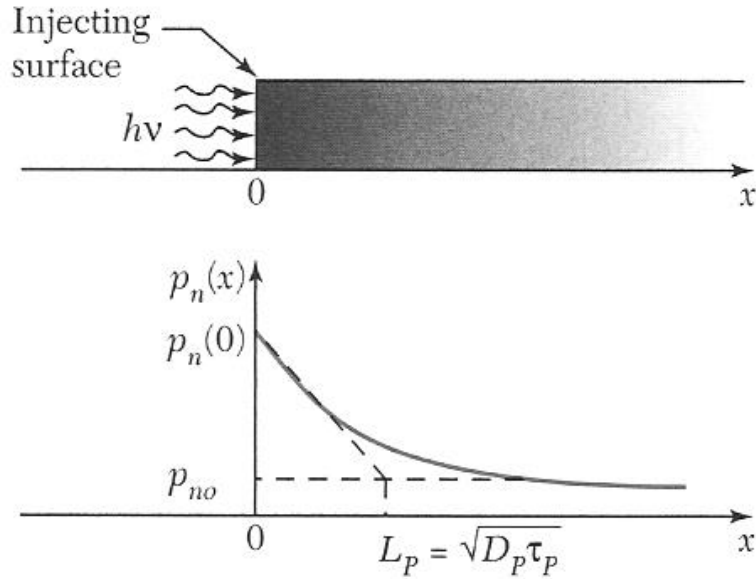
When the charge carriers are not in equilibrium the Fermi energy can be different for electrons and holes.

$$n = N_c \exp\left(\frac{E_{Fn} - E_c}{k_B T}\right)$$
$$p = N_v \exp\left(\frac{E_v - E_{Fp}}{k_B T}\right)$$



# Review of diffusion

n-type



$$D_p \frac{\partial^2 p_n}{\partial x^2} = \frac{p_n - p_{n0}}{\tau_p}$$

recombination time

$$p_n(x) = p_{n0} + (p_n(0) - p_{n0}) \exp\left(\frac{-x}{L_p}\right)$$

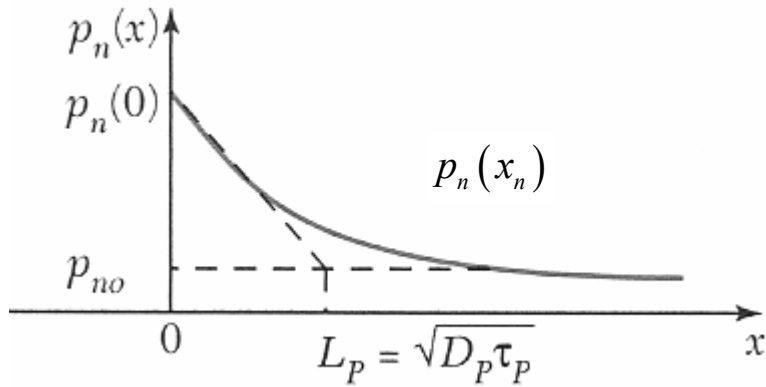
Injection only occurs at the surface.  
There the minority carrier density is  $p_n(0)$ .

$$L_p = \sqrt{D_p \tau_p}$$

diffusion length

# Diffusion current

n-type



$$p_n(x) = p_{n0} + (p_n(x_n) - p_{n0}) \exp\left(\frac{-x}{L_p}\right)$$

$$J_{diff,p} = -eD_p \frac{dp}{dx}$$

$$J_{diff,p} = -eD_p \frac{dp}{dx} = (p_n(x_n) - p_{n0}) \frac{eD_p}{L_p} \exp\left(\frac{-x}{L_p}\right)$$

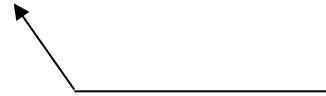
At the edge of the depletion region:

$$J_{diff,p} = -eD_p \frac{dp}{dx} = (p_n(x_n) - p_{n0}) \frac{eD_p}{L_p}$$

## Diffusion current

---

$$J_{diff,p} = (p_n(x_n) - p_{n0}) \frac{eD_p}{L_p}$$



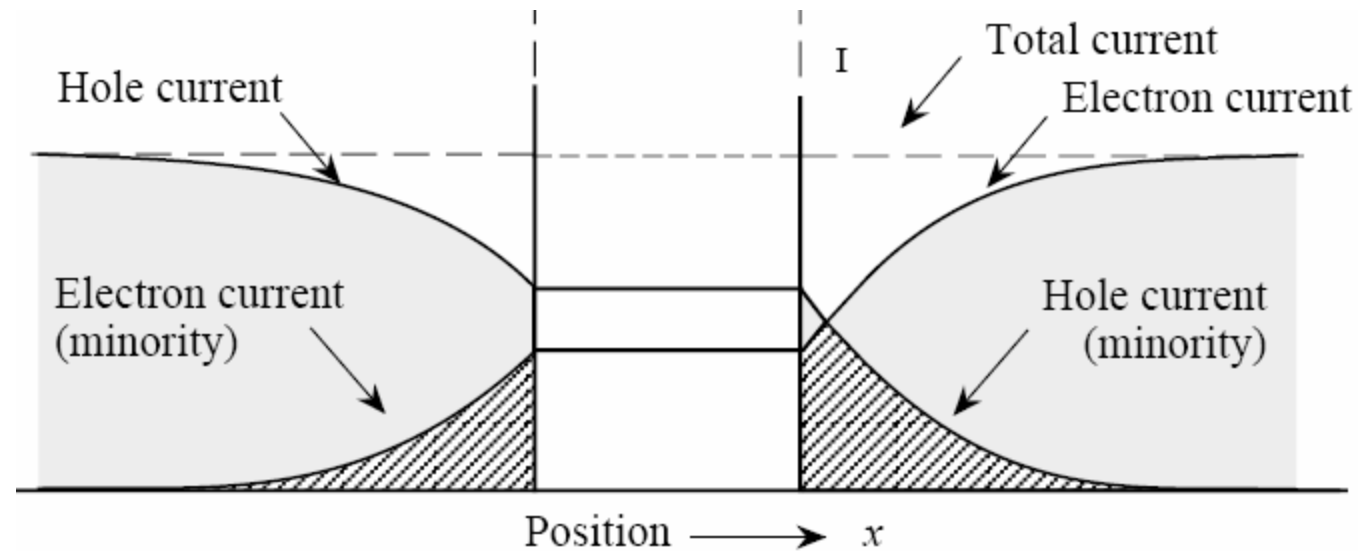
$$p_n(x_n) = p_{n0} \exp\left(\frac{eV}{k_B T}\right)$$

$$J_{diff,p} = p_{n0} \frac{eD_p}{L_p} \left( \exp\left(\frac{eV}{k_B T}\right) - 1 \right)$$

## Diffusion current

$$J_{diff,p} = \frac{p_{n0}eD_p}{L_p} \left( \exp\left(\frac{eV}{k_B T}\right) - 1 \right)$$

$$J_{diff,n} = \frac{n_{p0}eD_n}{L_n} \left( \exp\left(\frac{eV}{k_B T}\right) - 1 \right)$$

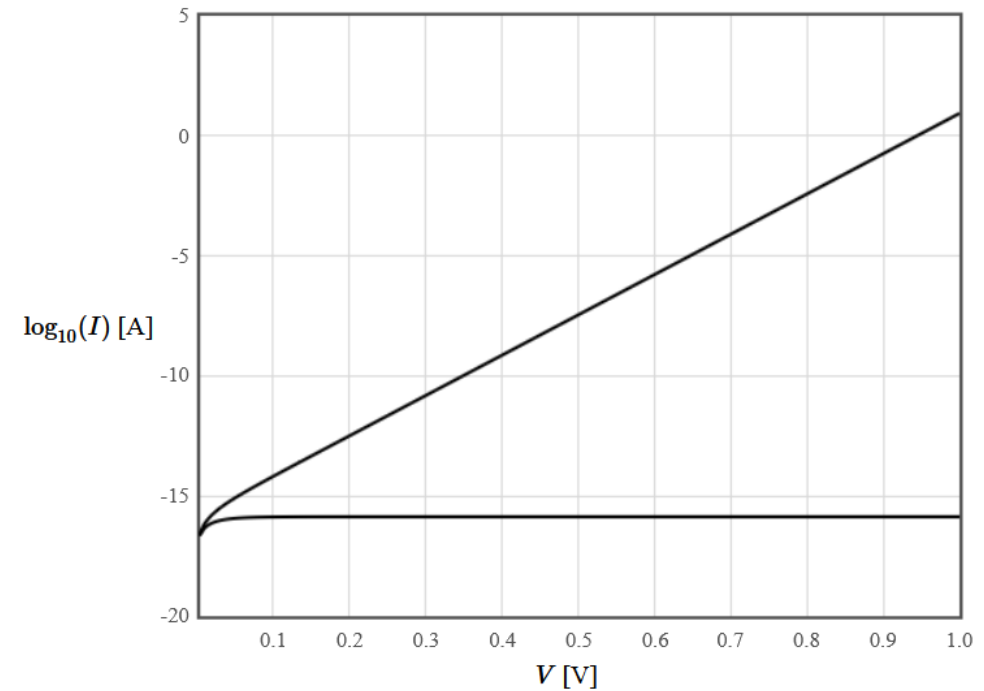
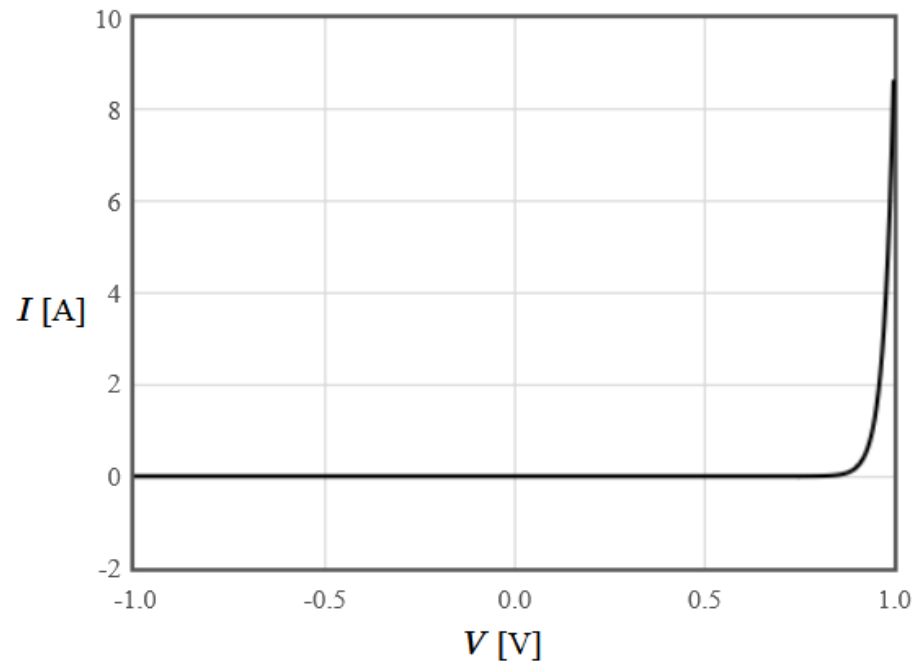


# Diode current

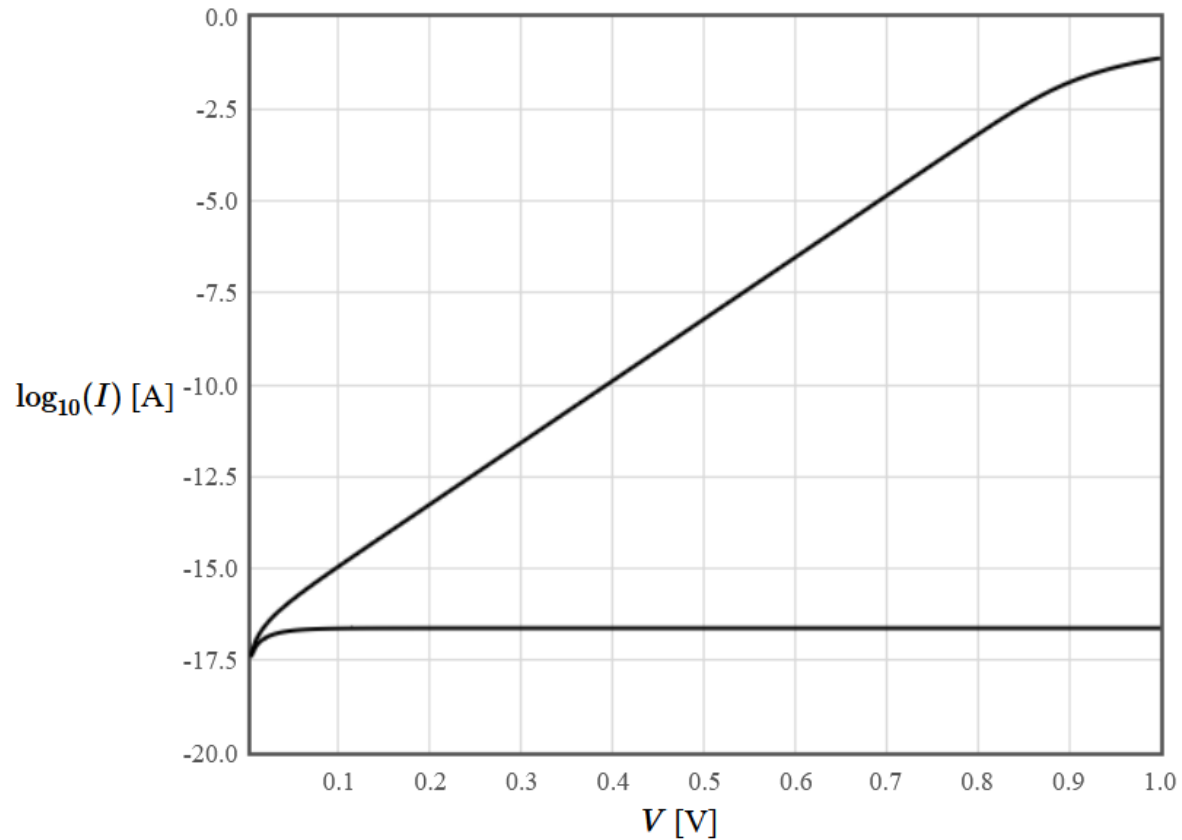
$$I = eA \left( \frac{p_{n0}D_p}{L_p} + \frac{n_{p0}D_n}{L_n} \right) \left( \exp\left(\frac{eV}{k_B T}\right) - 1 \right) = I_s \left( \exp\left(\frac{eV}{k_B T}\right) - 1 \right)$$

Area

Saturation current



# Diode I-V characteristics



$A = 1\text{E-}3$  cm<sup>2</sup>  
 $N_c(300\text{K}) = 2.78\text{E}19$  cm<sup>-3</sup>  
 $N_v(300\text{K}) = 9.84\text{E}18$  cm<sup>-3</sup>  
 $E_g = 1.166-4.73\text{E-}4*T*T/(T+636)$  eV

$\mu_p = 480$  cm<sup>2</sup>/Vs  
 $\tau_p = 1\text{E-}5$  s  
 $N_a = 1\text{E}17$  cm<sup>-3</sup>

$\mu_n = 1350$  cm<sup>2</sup>/Vs  
 $\tau_n = 1\text{E-}5$  s  
 $N_d = 5\text{E}17$  cm<sup>-3</sup>

$T = 300$  K  
 $V_{max} = 1$  V  
 $\eta = 1$   
 $R_S = 1$   $\Omega$

Replot

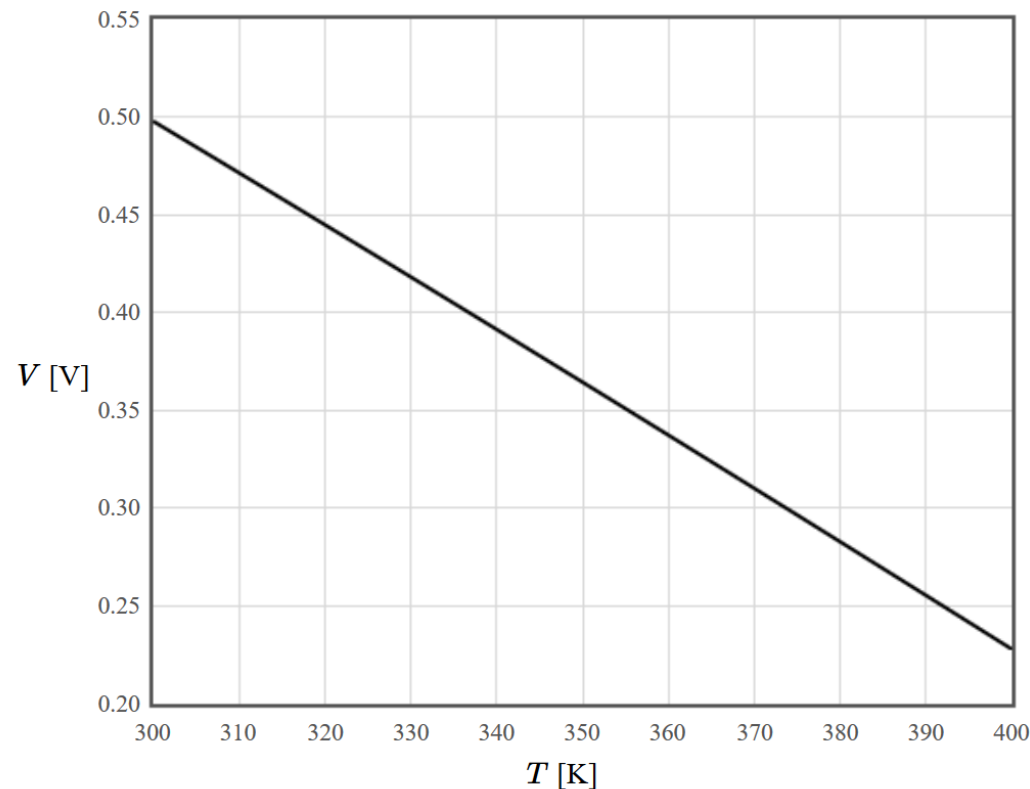
Si Ge GaAs

# Thermometer

$$I_S = Aen_i^2 \left( \frac{D_p}{L_p N_d} + \frac{D_n}{L_n N_a} \right)$$

$$n_i = \sqrt{N_c \left( \frac{T}{300} \right)^{3/2} N_v \left( \frac{T}{300} \right)^{3/2} \exp\left( \frac{-E_g}{2k_B T} \right)}$$

$$D_n = \frac{\mu_n k_B T}{e}$$



$A = 1\text{E-}3$  cm<sup>2</sup>  
 $N_c(300\text{K}) = 2.78\text{E}19$  cm<sup>-3</sup>  
 $N_v(300\text{K}) = 9.84\text{E}18$  cm<sup>-3</sup>  
 $E_g = 1.166 - 4.73\text{E-}4 * T * T / (T + 636)$  eV

$\mu_p = 480$  cm<sup>2</sup>/Vs  
 $\tau_p = 1\text{E-}8$  s  
 $N_a = 1\text{E}17$  cm<sup>-3</sup>

$\mu_n = 1350$  cm<sup>2</sup>/Vs  
 $\tau_n = 1\text{E-}8$  s  
 $N_d = 5\text{E}17$  cm<sup>-3</sup>

$T_{start} = 300$  K  
 $T_{stop} = 400$  K  
 $I = 1\text{E-}6$  A

Replot

Si

Ge

GaAs